

OptiMOS®-T2 Power-Transistor

AEC[®] © Qualified



Features

- N-channel Enhancement mode
- AEC qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green product (RoHS compliant)
- Ultra low Rds(on)
- 100% Avalanche tested

Туре	Package	Marking
IPB180N04S4-H0	PG-TO263-7-3	4N04H0

Maximum ratings, at T_j =25 °C, unless otherwise specified

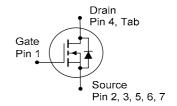
Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I _D	$T_{\rm C}$ =25°C, $V_{\rm GS}$ =10 $V^{1)}$	180	А
		T _C =100 °C, V _{GS} =10 V ²⁾	180	
Pulsed drain current ²⁾	I _{D,pulse}	T _C =25 °C	720	
Avalanche energy, single pulse	E _{AS}	/ _D =90 A	850	mJ
Avalanche current, single pulse	IAS	-	180	А
Gate source voltage	V_{GS}	-	±20	V
Power dissipation	P _{tot}	T _C =25 °C	250	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$	-	-55 +175	°C
IEC climatic category; DIN IEC 68-1	-	-	55/175/56	

Product Summary

V_{DS}	40	V
R _{DS(on)}	1.1	mΩ
I _D	180	Α

PG-TO263-7-3







Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics ²⁾						
Thermal resistance, junction - case	R _{thJC}	-	-	_	0.6	K/W
SMD version, device on PCB	R _{thJA}	minimal footprint	-	-	62	
		6 cm ² cooling area ³⁾	-	-	40	

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0 V, I _D = 1 mA	40	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 180 \ \mu {\rm A}$	2.0	3.0	4.0	
Zero gate voltage drain current	I _{DSS}	V _{DS} =40 V, V _{GS} =0 V, T _j =25 °C	1	0.08	1	μA
		$V_{\rm DS}$ =18 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =85 °C ²⁾	ı	1	20	
Gate-source leakage current	I _{GSS}	V _{GS} =20 V, V _{DS} =0 V	-	-	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10 V, I _D =100 A	-	0.9	1.1	mΩ



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics ²⁾						
Input capacitance	Ciss		-	13800	17940	pF
Output capacitance	C oss	V _{GS} =0 V, V _{DS} =25 V, f=1 MHz	-	3000	3900	
Reverse transfer capacitance	C _{rss}		-	100	230	
Turn-on delay time	t _{d(on)}		-	44	-	ns
Rise time	t _r	V _{DD} =20 V, V _{GS} =10 V,	-	24	-	
Turn-off delay time	t _{d(off)}	$I_{\rm D}$ =180 A, $R_{\rm G}$ =3.5 Ω	-	50	-	
Fall time	t _f]	-	49	-	
Gate Charge Characteristics ²⁾ Gate to source charge	Q _{gs}			71	92	nC
Gate to drain charge	Q _{gd}	$V_{\rm DD}$ =32 V, $I_{\rm D}$ =180 A, $V_{\rm GS}$ =0 to 10 V	_	23	53	
Gate charge total	Q _g		-	173	225	
Gate plateau voltage	V _{plateau}		-	5.0	-	V
Reverse Diode						
Diode continous forward current ²⁾	Is	T -25 °C	-	-	180	Α
Diode pulse current ²⁾	I _{S,pulse}	T _C =25 °C	-	-	720	1
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =100 A, T _j =25 °C	-	0.9	1.3	V
Reverse recovery time ²⁾	trr	V _R =20 V, I _F =50A, di _F /dt=100 A/μs	-	73	-	ns
Reverse recovery charge ²⁾	Q _{rr}		-	108	-	nC

¹⁾ Current is limited by bondwire; with an $R_{\rm thJC}$ = 0.6 K/W the chip is able to carry 367A at 25°C.

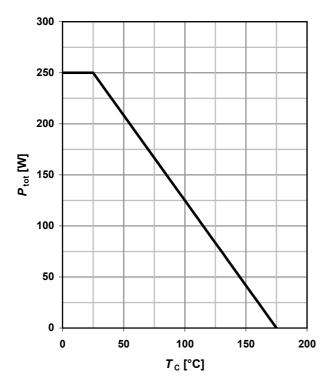
²⁾ Defined by design. Not subject to production test.

³⁾ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70 µm thick) copper area for drain connection. PCB is vertical in still air.



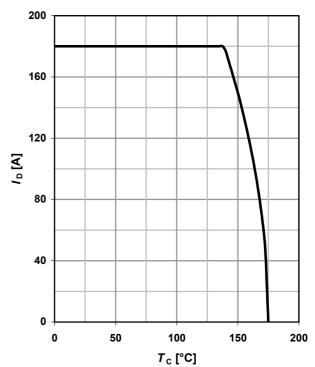
1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} \ge 6 \text{ V}$$



2 Drain current

$$I_D = f(T_C); V_{GS} \ge 6 \text{ V}$$



3 Safe operating area

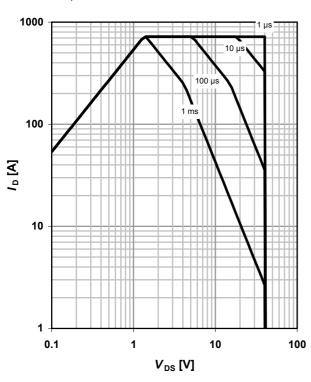
$$I_D = f(V_{DS}); T_C = 25 \,^{\circ}C; D = 0$$

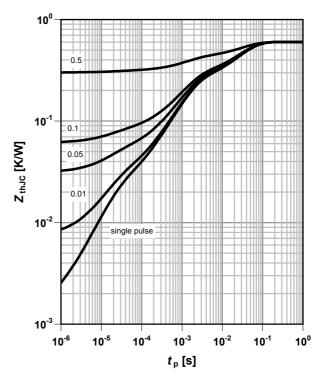
parameter: t_p

4 Max. transient thermal impedance

$$Z_{\rm thJC} = f(t_{\rm p})$$

parameter: $D = t_p/T$



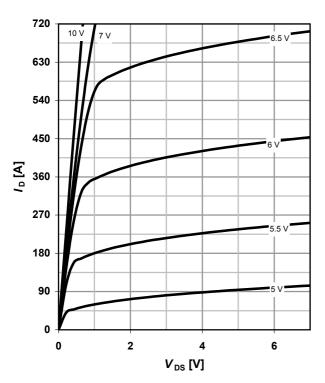




5 Typ. output characteristics

 $I_{\rm D} = f(V_{\rm DS}); T_{\rm j} = 25 \,{}^{\circ}{\rm C}$

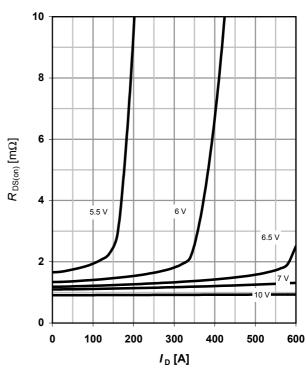
parameter: $V_{\rm GS}$



6 Typ. drain-source on-state resistance

 $R_{DS(on)} = (I_D); T_j = 25 \text{ }^{\circ}\text{C}$

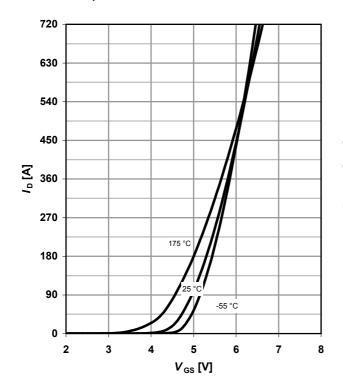
parameter: $V_{\rm GS}$



7 Typ. transfer characteristics

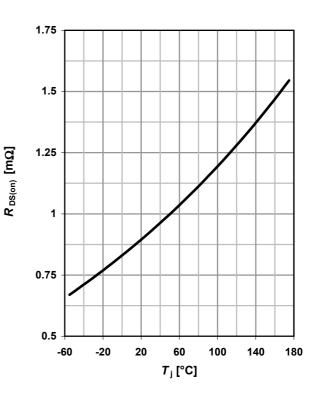
 $I_D = f(V_{GS}); V_{DS} = 6V$

parameter: T_i



8 Typ. drain-source on-state resistance

$$R_{DS(on)} = f(T_j); I_D = 100 \text{ A}; V_{GS} = 10 \text{ V}$$





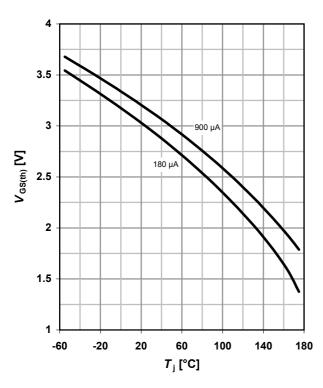
9 Typ. gate threshold voltage

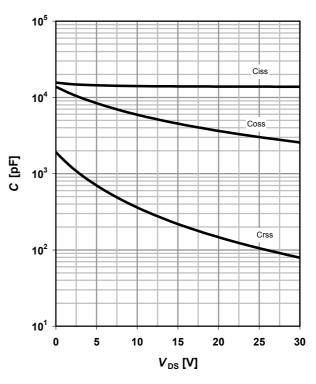
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: I_D

10 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$





11 Typical forward diode characteristicis

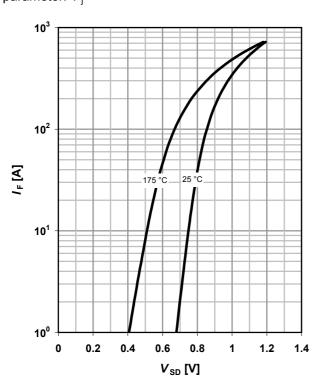
 $IF = f(V_{SD})$

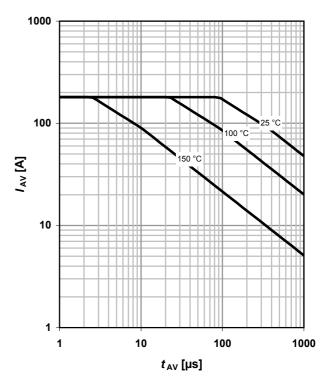
parameter: T_i

12 Typ. avalanche characteristics

 $I_{AS} = f(t_{AV})$

parameter: T_{j(start)}







13 Typical avalanche energy

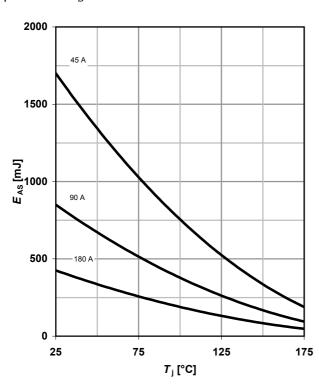
 $E_{AS} = f(T_i)$

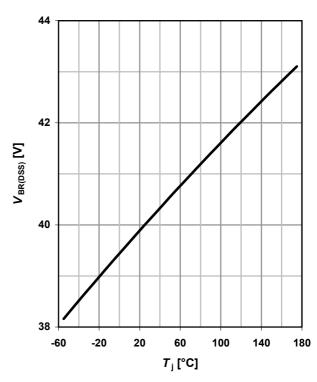
parameter: I_D

14 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$$

16 Gate charge waveforms

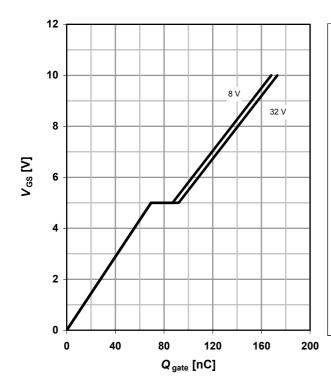


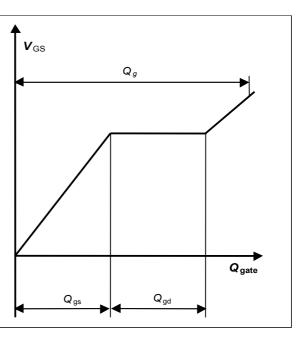


15 Typ. gate charge

 $V_{\rm GS}$ = f(Q $_{\rm gate}$); $I_{\rm D}$ = 180 A pulsed

parameter: $V_{\rm DD}$







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Revision History

Version	Date	Changes	
Revision 1.0	13.04.2010	Final Data Sheet	